

CHONGQING CLOUDCHILD TECHNOLOGY CO., LTD

# **TO-252-2L Plastic-Encapsulate MOSFETS**

# CCM060N04NTF N-Channel Power MOSFET

V <sub>DSS</sub>	R <sub>DS(ON)</sub> (Typ.)	ID
40V	<b>4.8</b> mΩ@10∨	70A

#### DESCRIPTION

The CCM060N04NTF provides excellent  $R_{DS(ON)}$  with low gate charge.

It can be used in a wide variety of applications.

#### FEATURES

- Trench Technology Power MOSFET
- Low R<sub>DS(ON)</sub>
- Low Gate Charge
- Low Gate Resistance
- 100% UIS Tested

#### APPLICATIONS

• Power switching application





M060N04N = Device Code

XX = Date Code

Solid Dot = Green Indicater



### ABSOLUTE MAXIMUM RATINGS(Ta=25°C unless otherwise noted)

Parameter		Symbol	Value	Unit
Drain - Source Voltage		V <sub>DS</sub>	40	V
Gate - Source Voltage		V <sub>GS</sub>	±20	V
Continuous Drain Current	T <sub>C</sub> = 25℃	lD	70	А
	T <sub>C</sub> = 100℃	ID	55	А
Pulsed Drain Current <sup>2</sup>		I <sub>DM</sub>	280	А
Single Pulsed Avalanche Current <sup>3</sup>		I <sub>AS</sub>	20.5	А
Single Pulsed Avalanche Energy <sup>3</sup>		Eas	105	mJ
Power Dissipation <sup>5</sup>	T <sub>C</sub> = 25℃	PD	42	W
Thermal Resistance from Junction to Ambient <sup>6</sup>		R <sub>θJA</sub>	53	°C/W
Thermal Resistance from Junction to Case		Rejc	3	°C/W
Junction Temperature		TJ	150	°C
Storage Temperature		Tstg	-55~ +150	°C

### MOSFET ELECTRICAL CHARACTERISTICS(Ta=25℃ unless otherwise noted)

Parameter	Symbol	Test Condition	Min	Туре	Мах	Unit	
Off Characteristics							
Drain - Source Breakdown Voltage	V(BR)DSS	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250µA	40			V	
Zero Gate Voltage Drain Current	IDSS	V <sub>DS</sub> = 40V, V <sub>GS</sub> = 0V			1	μA	
Gate - Body Leakage Current	lgss	$V_{GS}$ = ±20V, $V_{DS}$ = 0V			±100	nA	
On Characteristics <sup>4</sup>							
Gate Threshold Voltage	$V_{GS(th)}$	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250µA	1.0	1.7	3.0	V	
Drain source On registence	<b>D</b> ea()	V <sub>GS</sub> = 10V, I <sub>D</sub> = 15A		4.8	6.2		
	RDS(on)	V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 10A		5.6	8.5	_ mΩ	
Forward Transconductance	<b>g</b> fs	V <sub>DS</sub> = 5V, I <sub>D</sub> = 5A		36		S	
Dynamic Characteristics		_					
Input Capacitance	Ciss			3747			
Output Capacitance	Coss	V <sub>DS</sub> = 20V, V <sub>GS</sub> = 0V, f = 1MHz		238		pF	
Reverse Transfer Capacitance	Crss			210			
Gate Resistance	Rg	$V_{DS}$ = 0V, $V_{GS}$ = 0V, f = 1MHz		1.9		Ω	
Switching Characteristics							
Total Gate Charge	Qg			67			
Gate-source Charge	$Q_gs$	V <sub>DS</sub> = 20V, V <sub>GS</sub> = 10V, I <sub>D</sub> = 15A		9.6		nC	
Gate-drain Charge	$Q_gd$			12		1	
Turn-on Delay Time	t <sub>d(on)</sub>			7			
Turn-on Rise Time	tr	$V_{DD}$ = 20V, $V_{GS}$ = 10V, $R_{L}$ = 1 $\Omega$		15			
Turn-off Delay Ttime	t <sub>d(off)</sub>	R <sub>G</sub> = 3Ω		31		ns	
Turn-off Fall Time	t <sub>f</sub>			17			
Source - Drain Diode Characteristics							
Diode Forward Voltage <sup>4</sup>	Vsd	V <sub>GS</sub> = 0V, I <sub>S</sub> = 15A			1.2	V	
Diode Reverse Recovery Time	t <sub>rr</sub>	I <sub>F</sub> = 20A, dI/dt = 100A/µs		25		ns	
Diode Reverse Recovery Charge	Qrr	I <sub>F</sub> = 20A, dl/dt = 100A/μs		30		nC	

#### Notes :

- 1. The maximum current rating is limited by package. And device mounted on a large heatsink.
- 2. 2.Pulse Test : Pulse Width  $\leq$  10µs, duty cycle  $\leq$  1%.
- 3. EAS condition: VDD = 20V,VGS = 10V, L = 0.5mH, RG = 25 $\Omega$  Starting TJ = 25 $^\circ {\rm C}$  .
- 4. Pulse Test : Pulse Width  $\leq$  300µs, duty cycle  $\leq$  2%.
- 5. The power dissipation PD is limited by  $TJ(MAX) = 150^{\circ}C$ . And device mounted on a large heatsink.
- 6. Device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with TA =25°C.

## **Characteristics Curve:**









# **TO-252** Package Outline Dimensions







Cumhal	Dimensions In Millimeters		Dimensions In Inches		
Symbol	Min.	Max.	Min.	Max.	
Α	7.050	7.150	0.278	0.281	
A1	0.960	1.060	0.038	0.042	
A2	2.200	2.400	0.087	0.094	
A3	0.000	0.100	0.000	0.004	
b	0.760	DREF	0.030REF		
b1	1.000	1.000REF		9REF	
С	0.508REF		0.020REF		
c1	0.508	0.508REF		OREF	
D	6.550	6.650	0.258	0.262	
D1	5.100	5.460	0.201	0.215	
E	0.950	1.050	0.037	0.041	
E1	9.700	10.400	0.382	0.409	
E2	6.000	6.200	0.236	0.244	
e	2.286BSC		0.09	DBSC	
e1	4.572REF		0.18	OREF	
L	2.650	2.950	0.104	0.116	
L1	0.700	0.900	0.028	0.035	
<del>0</del> 1	7°REF		7°F	REF	
R	1.300REF		0.05	1REF	
R1	0.250	0.250REF		OREF	

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